

HY3704P-VB Datasheet

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS}	40	٧		
R _{DS(on)} V _{GS} = 10 V	2	mΩ		
I _D	180	Α		
Configuration	Single			

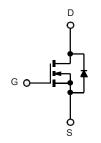
FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested

RoHS

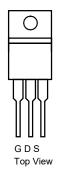
APPLICATIONS

- · Synchronous Rectification
- Power Supplies



N-Channel MOSFET

TO-220AB



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	40	V	
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C		180 ^{a, c}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C	-	150°		
Continuous Drain Current (1 _J = 175 C)	T _A = 25 °C	I _D	29 ^b	A	
	T _A = 70 °C		23 ^b		
Pulsed Drain Current		I _{DM}	350		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	80		
Single Pulse Avalanche Energy	L - 0.1 IIII	E _{AS}	320	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I-	110 ^{a, c}	A	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S _	2.6 ^b	A	
Maximum Power Dissipation	T _C = 25 °C		312ª		
	T _C = 70 °C	P _D	200	W	
	T _A = 25 °C	' D	3.13 ^b	vv	
	T _A = 70 °C		2.0 ^b		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.33	0.4	C/VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is $110\,\mathrm{A}$.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	Δ V _{DS} /T _J	I _D = 250 μA		41		mV/°C	
V _{GS(th)} Temperature Coefficient	Δ V _{GS(th)} /T _J	I _D – 230 μΑ		- 8			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Cata Maltana Duain Comment	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10 µA		
On-State Drain Currenta	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
	_	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$	2				
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		15		mΩ	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A		180		S	
Dynamic ^b							
Input Capacitance	C _{iss}			9000			
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		650		pF	
Reverse Transfer Capacitance	C _{rss}			450			
Total Gate Charge	Qg			120			
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		30		nC	
Gate-Drain Charge	Q _{gd}			16			
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		77	115		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			102	155	ns	
Rise Time	t _r	$V_{DD} = 20 \text{ V}, R_L = 1.0 \Omega$		62	95		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270		
Fall Time	t _f			60	90	1	
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			110		
Pulse Diode Forward Current ^a	I _{SM}				200	A	
Body Diode Voltage	V _{SD}	I _S = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 00 A di/dt = 400 A/r = T = 05 20		70	105	nC	
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		30			
Reverse Recovery Rise Time	t _b			20		ns	

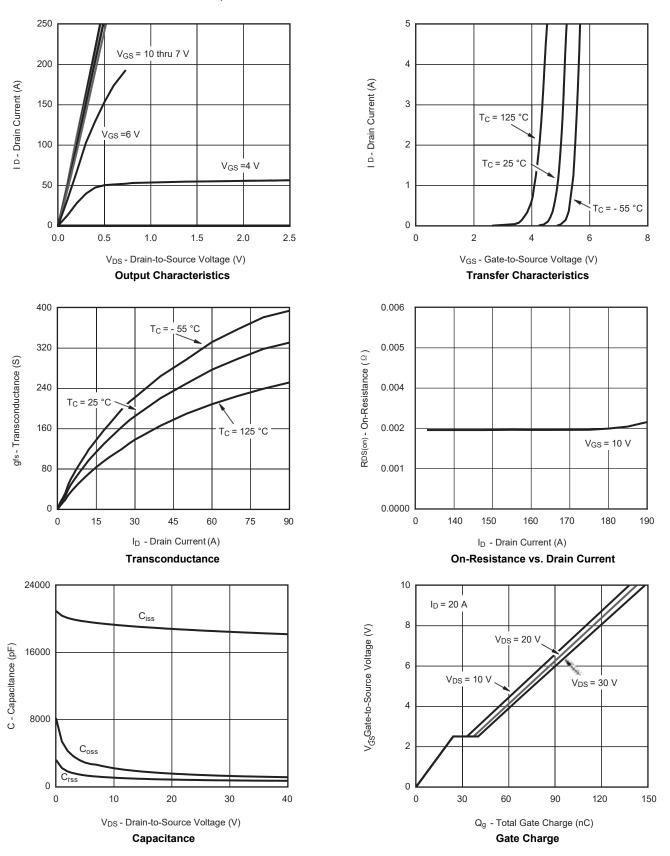
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

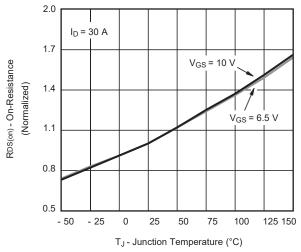


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

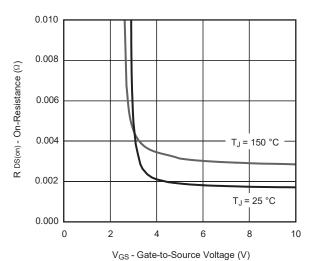




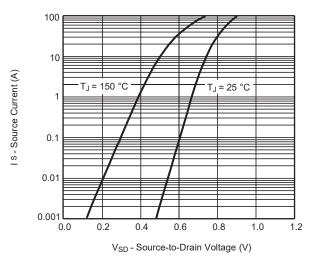
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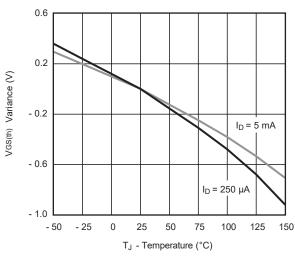
On-Resistance vs. Junction Temperature



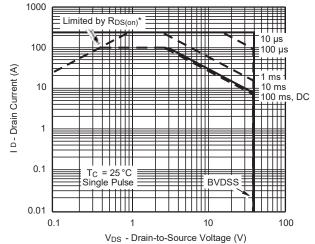
On-Resistance vs. Gate-to-Source Voltage



Forward Diode Voltage vs. Temperature



Threshold Voltage

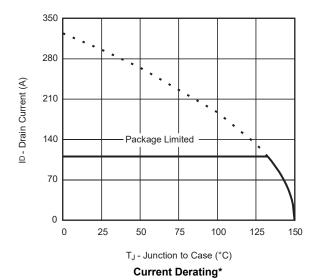


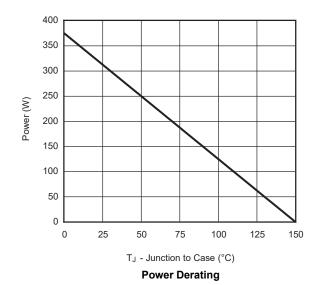
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

Safe Operating Area, Junction-to-Ambient

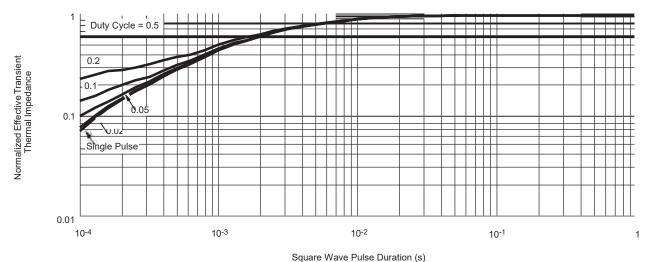


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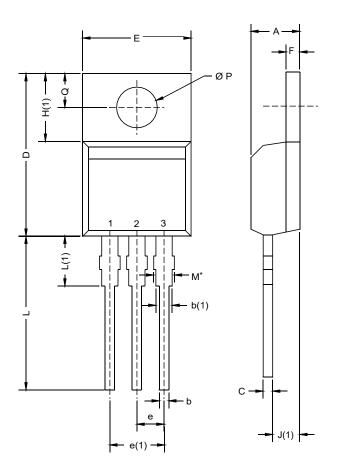
* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIM	ETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØΡ	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471						

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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